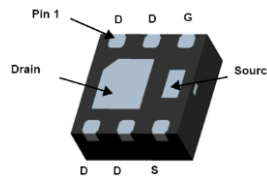
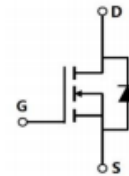


Main Product Characteristics:

V_{DSS}	30V
$R_{DS(on)}$	5.8mΩ(typ.)
I_D	18A


DFN2x2-6L
Pin Assignments

Schematic Diagram
Features and Benefits:

- Advanced trench MOSFET process technology
- Special designed for battery charge, load switching in cellular handset and general ultraportable applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


Description:

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in battery charge and load switching in cellular handset and a wide variety of other ultraportable applications

Absolute Max Rating:

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 4.5\text{V}^{\text{①}}$	18	A
I_{DM}	Pulsed Drain Current ^②	54	
$P_D @ T_C = 25^\circ\text{C}$	Power Dissipation ^③	16	W
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 20	V
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

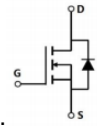
Thermal Resistance

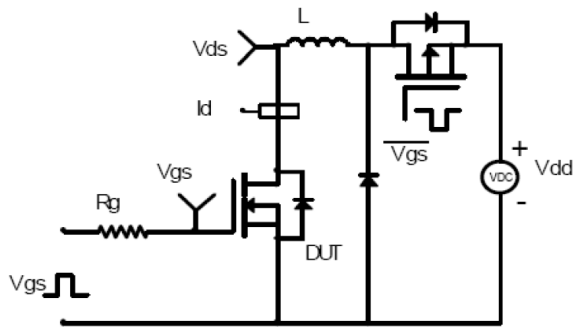
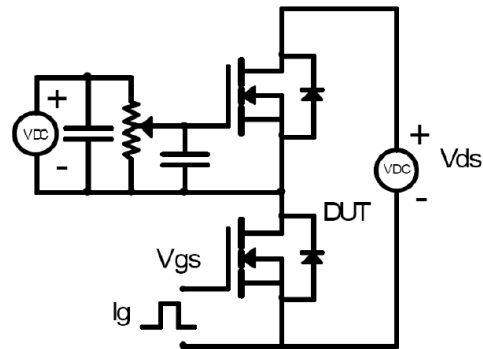
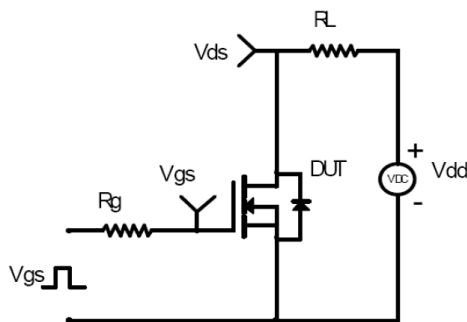
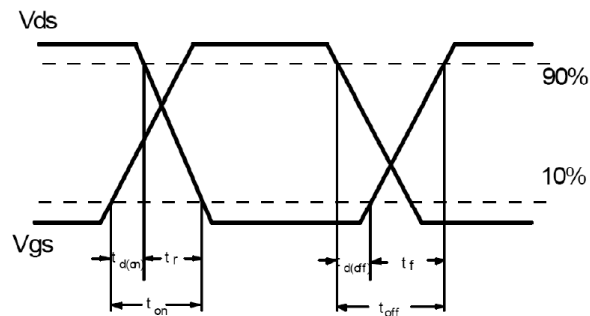
Symbol	Characterizes	Typ.	Max.	Units
R _{θJA}	Thermal Resistance, Junction-to-Ambient ④	—	35	°C/W

Electrical Characterizes @T_A=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	30	—	—	V	V _{GS} = 0V, I _D = 250μA
R _{DS(on)}	Static Drain-to-Source on-resistance	—	5.8	8	mΩ	V _{GS} = 10V, I _D = 15A
		—	9.6	14		V _{GS} = 4.5V, I _D = 10A
V _{GS(th)}	Gate threshold voltage	1	—	2.5	V	V _{DS} = V _{GS} , I _D = 250μA
I _{DSS}	Drain-to-Source leakage current	—	—	1	μA	V _{DS} = 30V, V _{GS} = 0V
I _{GSS}	Gate-to-Source forward leakage	—	—	100	nA	V _{GS} = 20V
		—	—	-100		V _{GS} = -20V
Q _g	Total gate charge	—	12.8	—	nC	I _D = 15A, V _{DD} = 15V, V _{GS} = 10V
Q _{gs}	Gate-to-Source charge	—	2.8	—		
Q _{gd}	Gate-to-Drain("Miller") charge	—	3.8	—		
t _{d(on)}	Turn-on delay time	—	8.2	—	nS	V _{GS} = 10V, V _{DS} = 22V, I _D = 10A, R _{GEN} = 2.2Ω
t _r	Rise time	—	19.2	—		
t _{d(off)}	Turn-Off delay time	—	23	—		
t _f	Fall time	—	5.6	—		
C _{iss}	Input capacitance	—	972	—	pF	V _{GS} = 0V V _{DS} = 30V f = 1MHz
C _{oss}	Output capacitance	—	141	—		
C _{rss}	Reverse transfer capacitance	—	7.8	—		

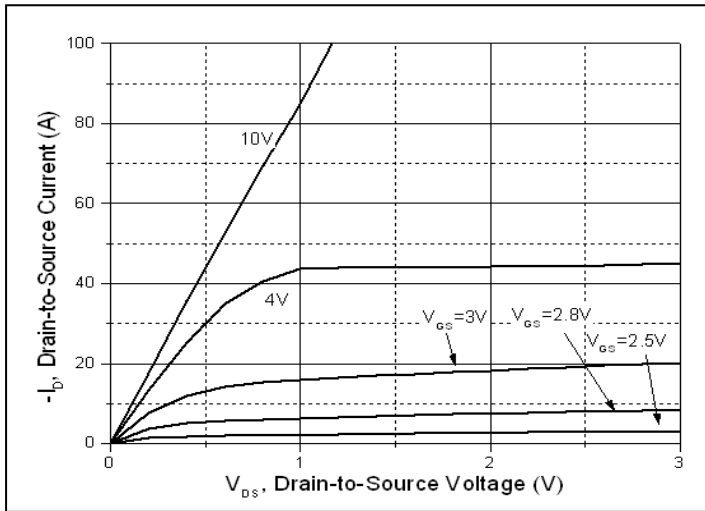
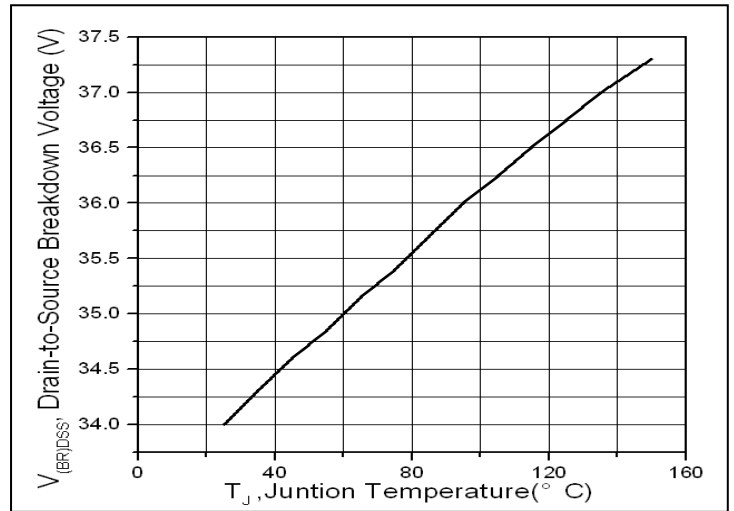
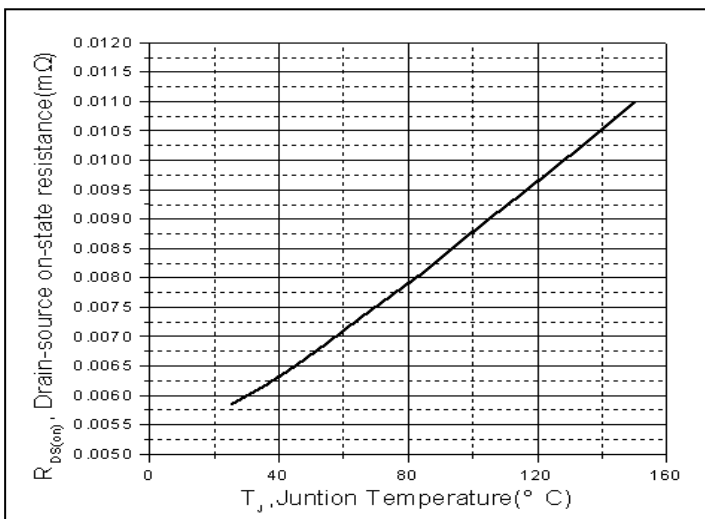
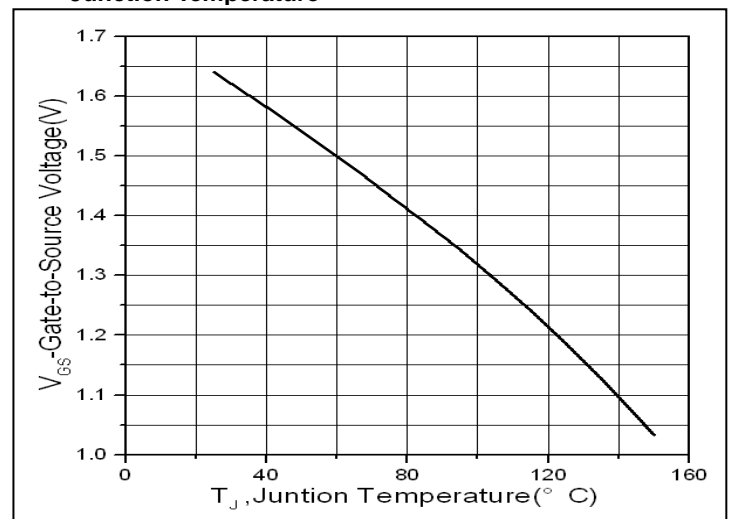
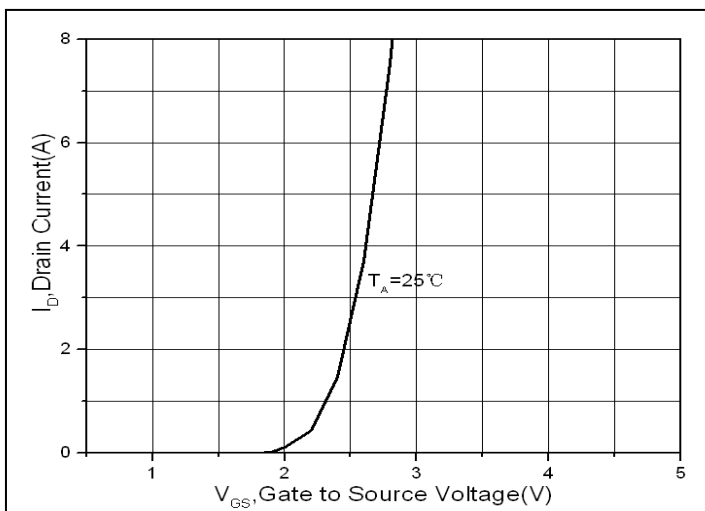
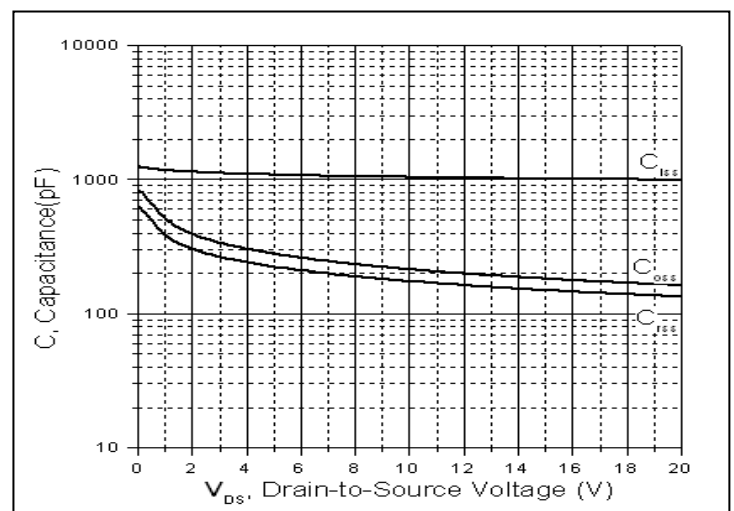
Source-Drain Ratings and Characteristics

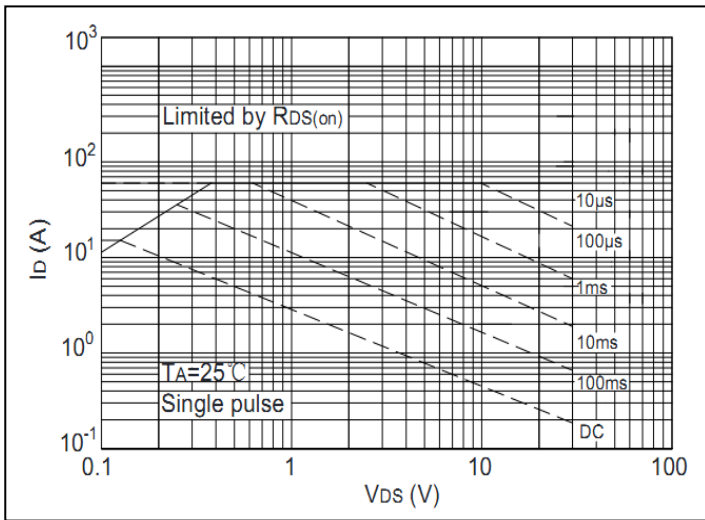
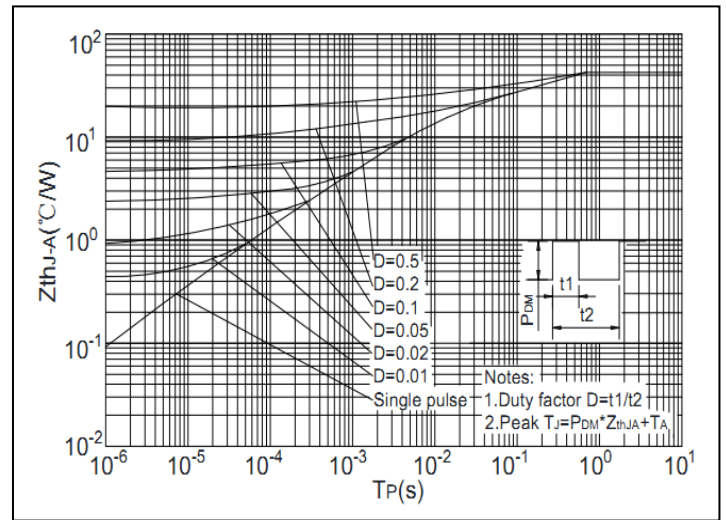
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)	—	—	18	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I _{SM}	Pulsed Source Current (Body Diode)	—	—	54	A	
V _{SD}	Diode Forward Voltage	—	0.87	1.2	V	I _S = 15A, V _{GS} = 0V
t _{rr}	Reverse Recovery Time	—	30	—	nS	T _J = 25°C, I _F = 15A, di/dt = 100A/μs
Q _{rr}	Reverse Recovery Charge	—	90	—	nC	

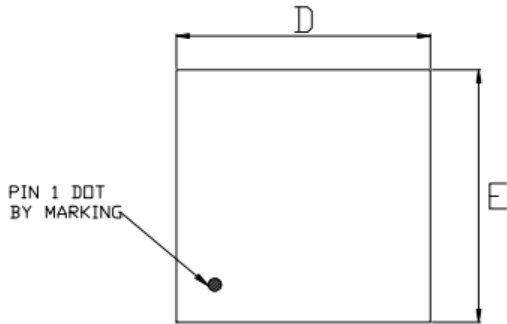
Test Circuits and Waveforms
EAS Test Circuit:

Gate Charge Test Circuit:

Switching Time Test Circuit:

Switching Waveforms:

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25\text{ }^\circ\text{C}$

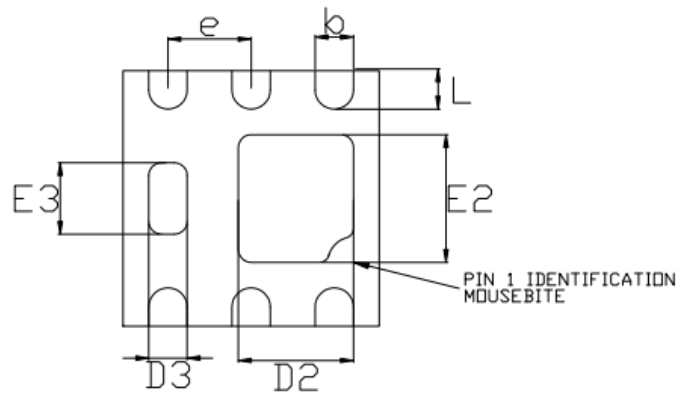
Typical Electrical and Thermal Characteristics


Figure1. Typical Output Characteristics

Figure2. Drain-to-Source Breakdown Voltage vs. Junction Temperature

Figure3. Normalized On-Resistance vs. Junction Temperature

Figure 4. Normalized $V_{GS(th)}$ vs. Junction Temperature

Figure5. Transfer Characteristics

Figure6. Capacitance

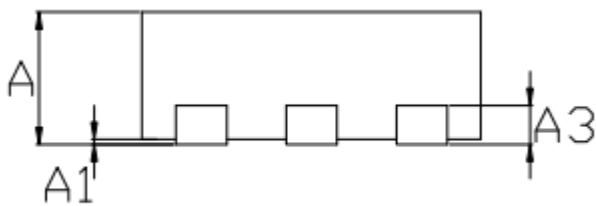
Typical Electrical and Thermal Characteristics

Figure 7. Safe Operation Area

Figure 8. Transient Thermal Impedance

Mechanical Data:
DFN 2 x 2-6L PACKAGE INFORMATION


TOP VIEW



BOTTOM VIEW



SIDE VIEW

COMMON DIMENSIONS(MM)			
PKG.	W:VERY VERY THIN		
REF.	MIN.	NOM.	MAX
A	0.70	0.75	0.80
A1	0.00	-	0.05
A3	0.20 REF.		
D	1.95	2.00	2.05
E	1.95	2.00	2.05
D2	0.85	0.90	0.95
E2	0.95	1.00	1.05
D3	0.25	0.30	0.35
E3	0.51	0.56	0.61
b	0.25	0.30	0.35
L	0.25	0.30	0.35
e	0.65 BSC		

Notes:

- ① Does not fully conform to JEDEC registration MO-229 dated Aug/2003.
- ② Dimensions are in millimeters.
- ③ Dimensions and tolerances per ASME Y14.5M. 1994.

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